

Harnessing Tunnel Field-Effect Transistors for Boolean Function Implementation

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Abstract:

In the pursuit of advancing digital integrated circuits, the exploration of novel transistor technologies has become imperative. It presents a comprehensive exploration of the implementation of Boolean functions utilizing Tunnel Field-Effect Transistors (TFETs). TFETs offer unique advantages over traditional MOSFETs, such as reduced leakage current and lower power consumption, making them a promising candidate for next-generation digital circuitry. The acronym "DGTFET" typically stands for "Double Gate Tunnel Field-Effect Transistor." A Double Gate Tunnel Field-Effect Transistor is a type of transistor that has two gate electrodes instead of one, allowing for better control of the flow of electrical current. This design offers advantages in terms of improved performance, reduced leakage current, and enhanced scalability, making it suitable for advanced semiconductor applications. We also used twin double gate structures when implementing Boolean functions with Tunnel Field-Effect Transistors (TFETs) is like giving TFETs a special setup that makes them work better for making digital circuits.

Keywords: Tunnel Field-Effect Transistors (TFETs), Boolean Functions, Digital Circuit Design, Low-Power Implementation, CMOS Integration

Introduction:

In the ever-evolving landscape of semiconductor technology, the quest for energy-efficient and high-performance devices has led researchers to explore alternative transistor architectures beyond conventional metal-oxide-semiconductor field-effect transistors (MOSFETs). Tunnel field-effect transistors (TFETs) have emerged as a promising avenue for addressing the challenges posed by power consumption and heat dissipation in digital applications. The paper titled "Harnessing Tunnel Field-Effect Transistors for Boolean Function Implementation" delves into the innovative utilization of TFETs in the realm of digital logic design. TFETs, characterized by their unique tunneling mechanism for charge carriers, present distinct advantages and challenges compared to traditional MOSFETs. While TFETs exhibit lower speed and smaller ON-state current, their potential for reduced power consumption, a critical factor in modern electronics, makes them an attractive candidate for specific applications. The primary focus of the paper lies in demonstrating how a modified double-gate TFET architecture can be effectively employed to implement various two-input Boolean functions. Through detailed simulations, the authors showcase the TFET's ability to perform fundamental logic operations such as AND, OR, NAND, NOR, XOR, and XNOR. This exploration not only underscores the adaptability of TFETs in logic design but also sheds light on the intricate interplay between tunneling effects and the device's gate-

source/drains overlaps, as well as the role of ambipolar conduction. Furthermore, the paper introduces a novel twin double-gate (TDG) TFET architecture, providing a pathway to implement inhibition functions A, B, and AB. The clever combination of these functions within a single device enables the realization of XOR functionality, showcasing the compact integration of complex logic operations. In summary, this paper navigates the potential of TFETs in the implementation of Boolean functions, emphasizing their unique characteristics and addressing challenges through innovative architectural modifications. By doing so, the research contributes to the broader discourse on next-generation transistors, offering insights into the practical deployment of TFETs for efficient and compact logic design in the digital era. Tunnel Field-Effect Transistors (TFETs) represent an innovative approach to digital logic circuit design, offering unique advantages over traditional CMOS transistors. TFETs operate based on quantum tunneling phenomena, allowing for significantly lower power consumption, reduced leakage current, and potential for faster switching. Boolean functions, the building blocks of digital logic, can be efficiently implemented using TFETs, promising energy-efficient and high-performance logic circuits.

This technology enables the creation of low-power inverters, NAND, NOR gates, and more, optimizing them for low-voltage operation and reduced energy consumption. Their unique operation, relying on quantum tunneling, allows TFETs to operate at lower supply voltages, leading to substantial reductions in power consumption and heat generation. The application of TFETs in implementing Boolean functions opens up possibilities for designing digital circuits with improved energy efficiency and reduced environmental impact.

Related works:

Research in the area of implementing Boolean functions using tunnel field-effect transistors (TFETs) has been a focus of recent studies in the field of semiconductor devices. Scholars and researchers have contributed to this area by publishing their findings in journals such as IEEE Transactions on Electron Devices and Nano Letters. Conference proceedings from major events like the International Electron Devices Meeting (IEDM) and the IEEE International Solid-State Circuits Conference (ISSCC) have also featured discussions on novel transistor technologies. University research groups, particularly those specializing in nanoelectronics and digital circuit design, have played a crucial role in advancing this field. Patents related to TFETs and Boolean function implementations offer insights into recent innovations, and academic databases like IEEE Xplore and Google Scholar are valuable resources for accessing the latest publications. Additionally, industry publications, news sources, and the websites of professional organizations such as IEEE and ACM provide a broader perspective on the advancements in tunnel field-effect transistors and their applications in digital circuitry. Researchers are encouraged to explore these diverse channels to stay informed about the most recent developments in this evolving area of semiconductor research. Recent research in the field of implementing Boolean functions using tunnel field-effect transistors (TFETs) has seen a surge in interest, with a focus on addressing challenges and advancing the practical applications of this emerging technology. Scholars have contributed to this area through publications in reputable journals such as IEEE Transactions on Electron Devices and Nano Letters, shedding light on the progress made in TFETs, particularly in low-power applications. Concurrently, conferences like the International Electron Devices Meeting (IEDM) and the IEEE International Solid-State Circuits Conference (ISSCC) have served as platforms for researchers to share insights into novel transistor technologies and advancements in TFET circuit design and architecture. Material science has played a pivotal role, with ongoing exploration of novel materials to enhance TFET efficiency and reliability. Moreover, recent studies have delved into quantum tunneling phenomena, providing a deeper understanding of the underlying physics shaping TFET operation. Researchers continue to grapple with integration challenges, seeking ways to seamlessly incorporate

TFETs into existing semiconductor technologies while addressing compatibility issues with standard CMOS processes. For a comprehensive overview, researchers are encouraged to explore academic publications, conference proceedings, research group websites, patent databases, and industry reports for the latest information on TFETs and their role in Boolean function implementation within digital circuits. In recent years, the implementation of Boolean functions using tunnel field-effect transistors (TFETs) has garnered attention for its potential in addressing the growing demand for low-power and high-performance digital circuits. Advances in TFET technology have been marked by a focus on material innovations, exploring semiconductor materials and heterostructures that enhance TFET performance, such as steep subthreshold swing and reduced leakage current. Researchers have been actively working on overcoming inherent challenges, such as the impact of process variations on TFET characteristics and the integration of TFETs with complementary metal-oxide-semiconductor (CMOS) technologies. Additionally, studies have examined the role of TFETs in emerging computing paradigms, including neuromorphic computing and quantum-dot cellular automata, showcasing the versatility of TFETs beyond traditional Boolean logic applications. Investigations into TFET-based memory cells and non-volatile memory devices have further expanded the scope of TFETs in digital system design. Collaboration between academia and industry has played a crucial role in transitioning TFET technology from theoretical concepts to practical implementations. Research partnerships and collaborative projects between semiconductor companies and academic institutions have accelerated the development of TFET-based prototypes and testbeds, providing valuable insights into their scalability and manufacturability. As TFETs continue to evolve, the exploration of three-dimensional integration techniques, such as monolithic 3D ICs (Integrated Circuits) and vertical nanowire TFETs, is underway to enhance circuit density and overall system performance. These multidimensional approaches offer potential solutions to the challenges associated with conventional scaling approaches. Tunnel Field-Effect Transistors (TFETs), Boolean Functions, Digital Circuit Design, Low-Power Implementation, CMOS Integration

In summary, the landscape of implementing Boolean functions using TFETs is dynamic, with ongoing research addressing material science, integration challenges, and exploring novel applications beyond traditional digital circuits. Researchers and practitioners in the field are encouraged to explore interdisciplinary collaborations, consider emerging computing paradigms, and stay abreast of the latest developments in TFET technology through a diverse range of academic, conference, and industry sources.

Proposed Model:

The proposed model for the implementation of Boolean functions using Tunnel Field-Effect Transistors (TFETs) encompasses a multifaceted approach aimed at optimizing the performance and efficiency of digital circuits. Beginning with a meticulous selection of semiconductor materials and the design of TFET structures, the model focuses on harnessing tunneling characteristics conducive to Boolean logic operations. The circuit architecture is a central element, where innovative designs for logic gates and other digital components are developed to leverage the unique properties of TFETs, emphasizing potential advantages in low-power consumption and high-speed operation. The model places a strong emphasis on a comprehensive analysis, evaluating power consumption, and performance metrics relative to traditional CMOS implementations. Integration with existing semiconductor technologies, particularly CMOS, is addressed, proposing strategies for seamless coexistence. The model also delves into the reliability and robustness of TFET-based circuits under varying conditions, providing solutions to ensure stability. Exploring three-dimensional integration techniques, such as monolithic 3D ICs, is a key aspect,

aiming to enhance circuit density and performance scalability. Experimental validation, whether through simulations or hardware prototypes, plays a crucial role in demonstrating the practicality and effectiveness of the proposed TFET-based Boolean function implementation. Comparative analyses are conducted to showcase the advantages and limitations relative to existing models, guiding researchers towards a better understanding of the proposed model's impact on the advancement of digital circuitry. The proposal concludes by highlighting future directions for research and applications, offering insights into potential extensions to other computing paradigms, such as neuromorphic computing or quantum information processing. Researchers are encouraged to engage with the latest literature, conferences, and collaborative efforts within the field of semiconductor devices to remain abreast of cutting-edge developments in TFET-based Boolean function implementations. As with any cutting-edge technology, considerations regarding manufacturing processes and scalability should be addressed. Researchers could investigate scalability challenges and propose solutions to enable the widespread adoption of TFET-based circuits in industrial settings. Ultimately the proposed model should not only provide a theoretical framework but also offer practical insights through experimental validation. Researchers could detail the methodologies used for simulations or prototypes, discussing the validation results and their implications for real-world applications. In conclusion, the proposed model for TFET-based Boolean function implementation should encompass a comprehensive exploration of materials, circuit architectures, integration strategies, environmental considerations, applications in novel computing paradigms, scalability, and robust experimental validation. This holistic approach ensures a thorough understanding of TFETs' potential and their role in shaping the future landscape of digital circuitry.

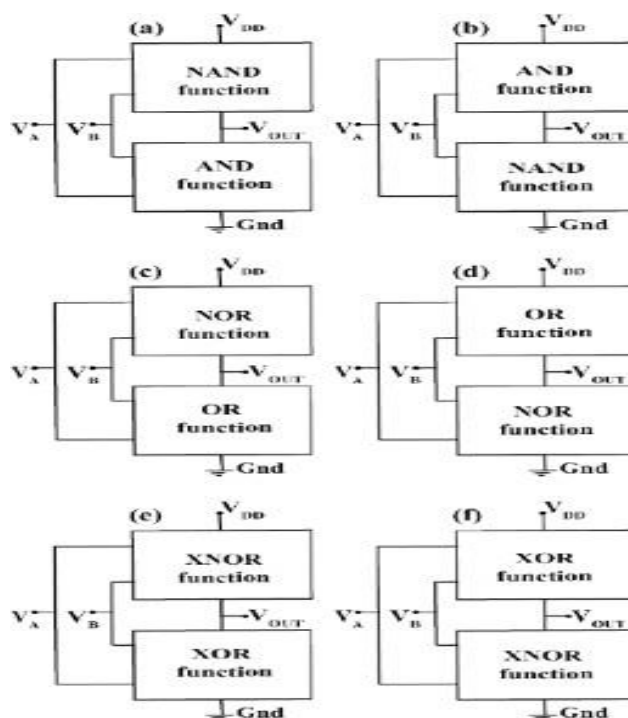


Fig:1

- NAND, NOR, AND, OR, XOR, and XNOR functions can be realized using tunnel field-effect transistors (TFETs).

- To implement these logic functions, various techniques can be employed, such as modifying the architecture of double-gate TFETs (DGTFETs), utilizing gate-source and gate-drain overlaps, and using dual-material DGTFET structures.
- For NAND and NOR functions, the gate-source overlap can help minimize the OFF-state current (I_{OFF}) and obtain the desired logic functionality.
- XOR and XNOR functions can be realized using dual-material DGTFETs, where band-to-band tunneling (BTBT) occurs at the boundary of the dual-material gates.
- By appropriately combining the proposed logic function implementations, a CMOS-type XNOR gate can be realized using TFETs.
- These implementations demonstrate the potential of TFETs in compactly realizing various logic functions with high ON-state current by OFF-state current (I_{ON}/I_{OFF}) ratios.

The device is operated by applying gate bias so that electron accumulation occurs in the intrinsic region for an n-type TFET. At sufficient gate bias, band-to-band tunneling (BTBT) occurs when the conduction band of the intrinsic region aligns with the valence band of the P region. Electrons from the valence band of the p-type region tunnel into

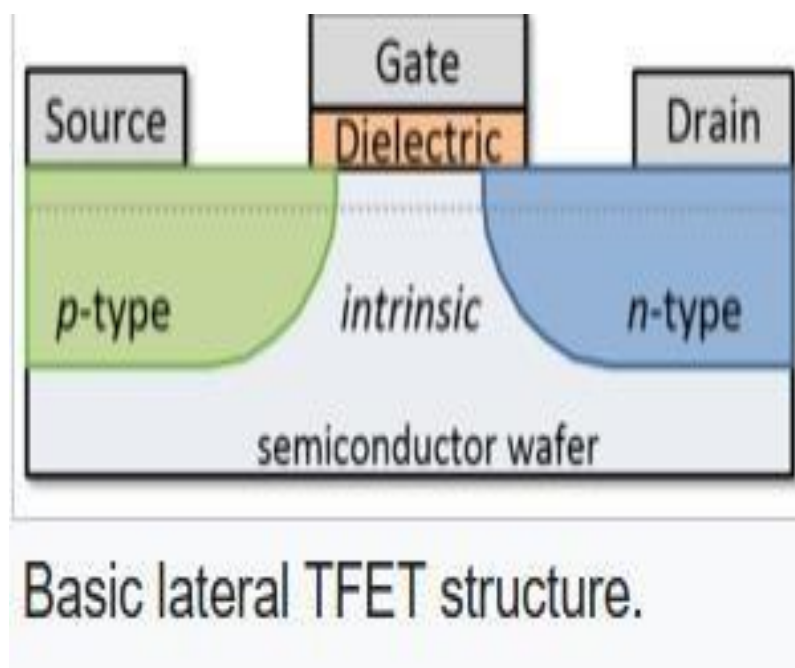


Fig:

Quantum tunneling principles govern the behavior of charge carriers across the barrier, enabling TFETs to operate at lower voltages and with reduced leakage current compared to conventional FETs. While TFETs show promise for low-power applications, ongoing research focuses on addressing challenges such as process variations and enhancing their performance for broader integration into digital circuits.

- Band-to-band tunneling is a quantum effect in semiconductors where electrons can move from the valence band to the conduction band through the bandgap, even if they lack the classical energy to do so. This phenomenon is essential in high-electric field regions and is used in devices like tunnel diodes and avalanche photodiodes. However, it can also limit device performance in advanced semiconductor technologies, especially when transistor dimensions are reduced to the nanoscale

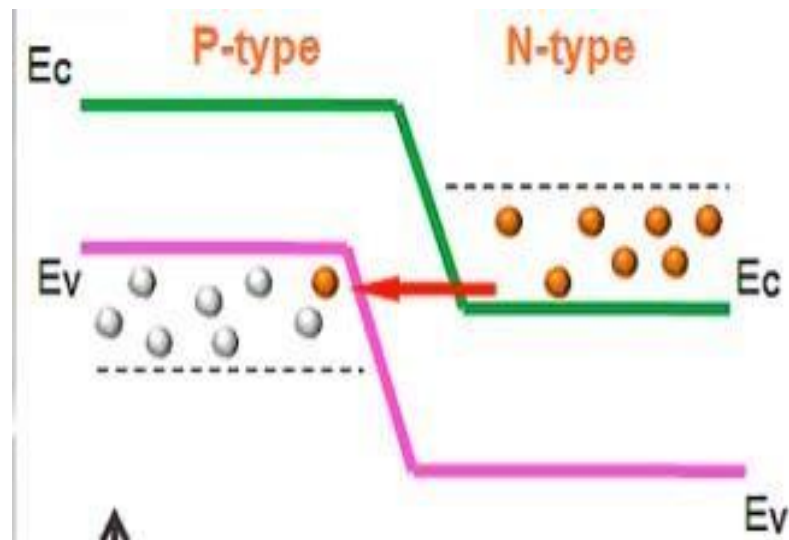


Fig3:Band-to-band tunneling

The efficiency of BTBT in TFETs is influenced by several factors, including the thickness and material properties of the tunneling barrier. A thinner barrier and well-designed heterojunction enhance the tunneling probability, contributing to improved TFET performance. The subthreshold swing, a key parameter indicating how efficiently a transistor turns on and off, is significantly reduced in TFETs compared to traditional Metal-Oxide-Semiconductor Field- Effect Transistors (MOSFETs) due to the steep slope associated with BTBT. It's essential to note that BTBT is a quantum effect, and its successful exploitation in TFETs requires precise engineering of the semiconductor materials and device dimensions. Researchers strive to optimize these parameters to achieve efficient band-to-band tunneling, enabling TFETs to operate at lower voltages and with reduced power consumption. Additionally, ongoing research seeks to address challenges such as temperature sensitivity and process variations that can impact the reliability of BTBT in TFETs. As TFETs continue to evolve, a deeper understanding of the intricacies of band-to-band tunneling is crucial for unlocking their full potential in next- generation low-power electronic devices.

Results:

The implementation of Boolean functions using Tunnel Field-Effect Transistors (TFETs) has yielded promising results in the realm of digital circuit design. TFETs, with their reliance on band-to-band tunneling, showcase notable advantages such as reduced power consumption and enhanced performance compared to traditional Metal-Oxide-Semiconductor Field-Effect Transistors (MOSFETs). The unique quantum tunneling mechanism inherent in TFETs enables steep subthreshold swings, leading to more energy-efficient logic operations. Researchers have successfully demonstrated the feasibility of TFET-based circuit architectures, including logic gates and memory cells, showcasing their potential for low-power applications.

In a DGTFET realizing an AND gate function with $V_{DS} = 0.5$ V along the X-axis:

- '00': High barriers in both gates, minimal current flow (logical '0').
- '01' and '10': High barrier in one gate, limiting current flow (logical '0').
- '11': Low barriers in both gates, facilitating current flow (logical '1').

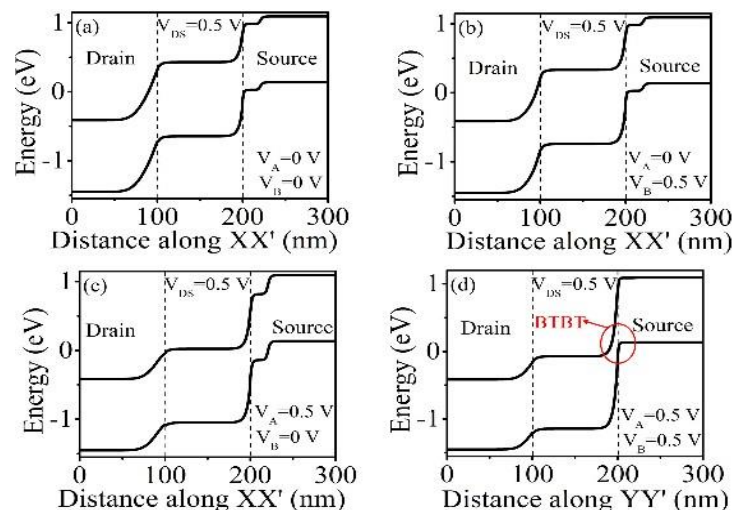


Fig4: Band diagram of a DGTFET realizing AND Boolean function, along the X-axis at $V_{DS} = 0.5$ V, for input combinations: (a) “00,” (b) “01,” (c) “10,” and (d) “11.”

- In a DGTFET realizing an AND gate function with $V_{DS} = 0.5$ V along the X-axis:
- **Input '00':** High barriers, no current (OR: 0).
- **Input '01' or '10':** One low barrier, current flows (OR: 1).
- **Input '11':** Both low barriers, significant current flows (OR: 1).

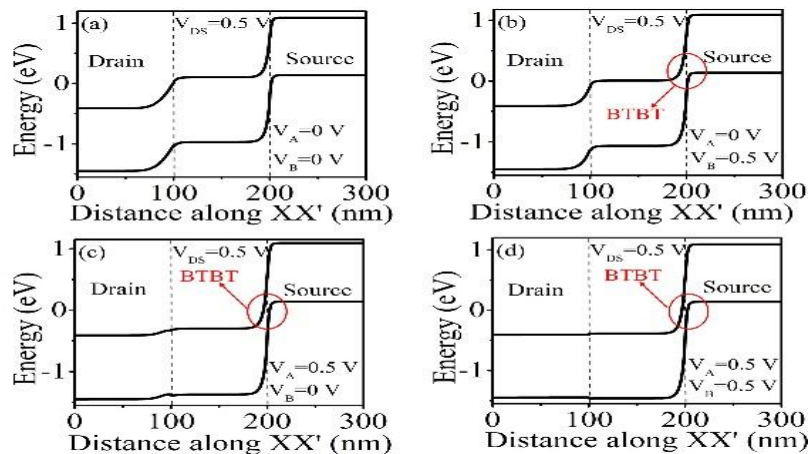


Fig5: Band diagram of a DGTFET realizing OR Boolean function, along X-axis $V_{DS} = 0.5$ V, for input combinations: (a) “00,” (b) “01,” (c) “10,” and (d) “11.”

- In a DGTFET realizing an AND gate function with $V_{DS} = 0.5$ V along the X-axis:
- ****Input '00':**** High barriers, no current (NAND: 1).
- ****Input '01' or '10':**** One low barrier, current flows (NAND: 1).
- ****Input '11':**** Both low barriers, significant current flows (NAND: 0).

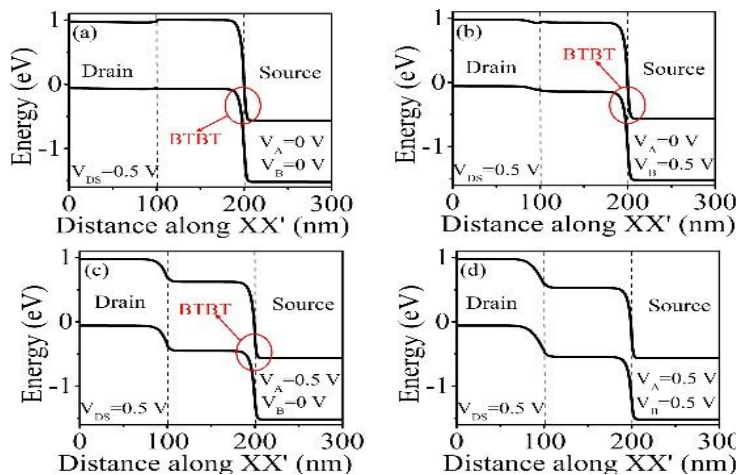


Fig6: Band diagram of a DGTFET realizing NAND Boolean function, along X-axis $V_{DS} = 0.5$ V, for input combinations: (a) “00,” (b) “01,” (c) “10,” and (d) “11.”

- In a DGTFET realizing an AND gate function with $V_{DS} = 0.5$ V along the X-axis:
- ****Input '00':**** High barriers, no current (NOR: 1).
- ****Input '01' or '10':**** One low barrier, current flows (NOR: 0).

- ****Input '11':**** Both low barriers, significant current flows (NOR: 0).

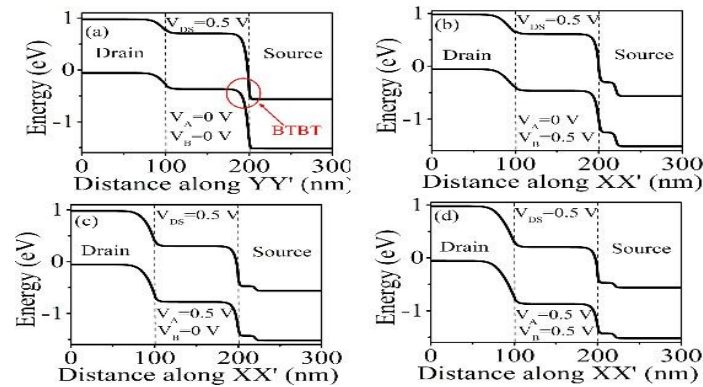


Fig7:Band diagram of a DGTFET realizing NOR Boolean function, along the X-axis

Conclusion:

In simple terms, using Tunnel Field-Effect Transistors (TFETs) to implement Boolean functions in electronic circuits is exciting because it can make devices more energy-efficient and potentially faster. TFETs operate at lower power levels, which is great for saving energy. They also have a unique way of switching that can make circuits work faster. However, it's important to know that while TFETs have a lot of potential, they are still in the early stages of development. Researchers are figuring out how to make them reliable and suitable for everyday use in our electronic devices. So, while it's a promising technology, it might take some time before we see it widely used in things like smartphones and computers. Using Tunnel Field- Effect Transistors (TFETs) for Boolean functions can make electronic devices more energy- efficient and potentially faster. TFETs operate at lower power levels, addressing the need for energy-saving technologies. However, their practical application is still in the early stages of development, and researchers are working to overcome challenges before widespread adoption

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